

FORM PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. ASMMC.013C2	APPLICATION NO. To be assigned
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (USE SEVERAL SHEETS IF NECESSARY)		APPLICANT Suntola et al.	
		FILING DATE Concurrently herewith	GROUP Unknown


J1001 U.S. PTO
 09/855321
 05/14/01

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
EF	1	3,730,696	05/1973	Pointu et al.			
EF	2	4,058,430	11/1977	Suntola et al.			
EF	3	4,062,318	12/1977	Ban et al.			
EF	4	4,263,872	04/1981	Ban			
EF	5	4,339,645	07/1982	Miller			
EF	6	4,389,973	06/1983	Suntola et al.			
EF	7	4,413,022	11/1983	Suntola et al.			
EF	8	4,421,786	12/1983	Mahajan et al.			
EF	9	4,825,806	05/1989	Tawada et al.			
EF	10	4,861,417	08/1989	Mochizuki et al.			
EF	11	4,876,218	10/1989	Pessa et al.			
EF	12	4,975,252	12/1990	Nishizawa et al.			
EF	13	4,993,357	02/1991	Scholz			
EF	14	5,038,711	08/1991	Dan et al.			
EF	15	5,091,335	02/1992	Grunthaner et al.			
EF	16	5,183,510	02/1993	Kimura			
EF	17	5,270,247	12/1993	Sakuma et al.			
EF	18	5,395,791	03/1995	Cheng et al.			
EF	19	5,429,068	07/1995	Sakuma			
EF	20	5,711,811	01/1998	Suntola et al.			

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
EF	21	JP 1-305524	12/1989	Japan				
EF	22	61-289623	12/1986	Japan				
EF	23	61-26217	02/1986	Japan				

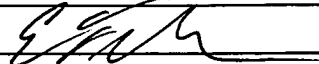
EXAMINER		DATE CONSIDERED	8/13/03
*EXAMINER: INITIAL IF CITATION CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP 609; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED, INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT.			

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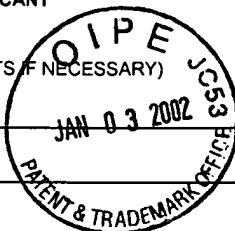
FOREIGN PATENT DOCUMENTS								
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
EP	24	39 36 016 A1	10/1989	Germany				
EP	25	37 39 528 A1	11/1987	Germany				
EP	26	31 48 620 C2	05/1981	Germany				
EP	27	0015390 A1	09/1980	Europe				
EP	28	0559326 A1	09/1993	Europe				

EXAMINER INITIAL	OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)	
EP	29	Garache et al., "Deposit and Clean Deposition System," <i>IBM Technical Disclosure Bulletin</i> , Vol. 13, No. 7, p. 2083 (December 1970).
EP	30	Suntola, "Atomic Layer Epitaxy," <i>Thin Solid Films</i> , Vol. 216, pp. 84-89 (1992).
EP	31	Patent Abstracts of Japan, Vol. 12, No. 358, C-531, abstract of JP A 63-112495 (May 17, 1988).
EP	32	Patent Abstracts of Japan, Vol. 8, No. 225, C-247, abstract of JP A 59-111997 (June 28, 1984).

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FORM PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. ASMMC.013C2	APPLICATION NO. 09/855,321
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (USE SEVERAL SHEETS IF NECESSARY)		APPLICANT SUNTOLA et al.	
		FILING DATE May 14, 2001	GROUP 1763



U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)

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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
EP	1	1-264993	1989 10 23	Japan				
EP	2	51-77589	1976 07 05	Japan				
EP	3	55-130896	1980 10 11	Japan				
EP	4	6-216030	1994 08 05	Japan				

EXAMINER INITIAL	OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)	

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EXAMINER		DATE CONSIDERED	3/13/03
*EXAMINER: INITIAL IF CITATION CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP 609; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED, INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT.			

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APPLICANT
SUNTOLA et al.FILING DATE
May 14, 2001GROUP
1763

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FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
EF	1	0 273 470 A3	06.07.88	EPO	C23C	16/44		
EF	2	0 379 594 A1	01.08.90	EPO	C23C	16/44		

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SUNTOLA et al.FILING DATE
May 14, 2001GROUP
1763

EXAMINER INITIAL	OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)	
EP	1.	Claim Construction of United States Patents Nos. 6,015,590, 5,916,365 and 5,294,568; filed August 15, 2002

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EXAMINER



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